

## PSMN0R9-30YLD

N-channel 30 V, 0.87 m $\Omega$  logic level MOSFET in LFPAK56 using NextPowerS3 Technology

7 October 2013

Objective data sheet

## 1. General description

Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETs with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

### 2. Features and benefits

- Ultra low Q<sub>G</sub>, Q<sub>GD</sub> and Q<sub>OSS</sub> for high system efficiency, especially at higher switching frequencies
- Superfast switching with soft-recovery; s-factor > 1
- Low spiking and ringing for low EMI designs
- Unique "SchottkyPlus" technology; Schottky-like performance with < 1 μA leakage at 25 °C
- Optimised for 4.5 V gate drive
- Low parasitic inductance and resistance
- High reliability clip bonded and solder die attach Power SO8 package; no glue, no wire bonds, gualified to 175 °C
- Wave solderable; exposed leads for optimal visual solder inspection

## 3. Applications

- On-board DC-to-DC solutions for server and telecommunications
- Secondary-side synchronous rectification in telecommunication applications
- Voltage regulator modules (VRM)
- Point-of-Load (POL) modules
- Power delivery for V-core, ASIC, DDR, GPU, VGA and system components
- · Brushed and brushless motor control
- Power OR-ing

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C		-	-	30	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 10 V; <u>Fig. 1</u>	[1]	-	-	100	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	-	349	W





Symbol	Parameter	Conditions	Min	Тур	Max	Unit
T <sub>j</sub>	junction temperature		-55	-	175	°C
Static chara	acteristics				'	
R <sub>DSon</sub>	drain-source on-state	$V_{GS}$ = 4.5 V; $I_D$ = 25 A; $T_j$ = 25 °C	-	0.97	1.09	mΩ
	resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C	-	0.77	0.87	mΩ
Dynamic cl	haracteristics				-	
$Q_{GD}$	gate-drain charge	$V_{GS}$ = 4.5 V; $I_{D}$ = 25 A; $V_{DS}$ = 15 V; Fig. 7	-	[tbd]	-	nC
Q <sub>G(tot)</sub>	total gate charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; V_{DS} = 15 \text{ V};$ Fig. 7	-	[tbd]	-	nC
Source-dra	in diode		· · · · · · · · · · · · · · · · · · ·			
S	softness factor	$I_S$ = 25 A; $V_{GS}$ = 0 V; $dI_S/dt$ = -100 A/ $\mu$ s; $V_{DS}$ = 15 V; Fig. 8	-	[tbd]	-	

<sup>[1]</sup> Continuous current is limited by package.

## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		D
2	S	source		
3	S	source		G_UN4)
4	G	gate		mbb076 S
mb	D	mounting base; connected to drain	1 2 3 4	
			LFPAK56; Power- SO8 (SOT1023)	

## 6. Ordering information

Table 3. Ordering information

Type number	Package					
	Name	Description	Version			
PSMN0R9-30YLD	LFPAK56; Power-SO8	Plastic single-ended surface-mounted package (LFPAK56); 4 leads	SOT1023			

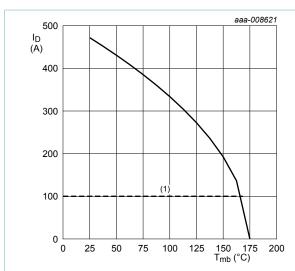
#### **Limiting values 7**.

Table 4. **Limiting values** 

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C		-	30	V
$V_{DGR}$	drain-gate voltage	25 °C ≤ T <sub>j</sub> ≤ 175 °C; R <sub>GS</sub> = 20 kΩ		-	30	V
$V_{GS}$	gate-source voltage			-20	20	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>	[1]	-	100	Α
		V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 100 °C; <u>Fig. 1</u>	[1]	-	100	Α
I <sub>DM</sub>	peak drain current	pulsed; $t_p \le 10 \mu s$ ; $T_{mb} = 25 \text{ °C}$		-	1888	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	349	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
T <sub>sld(M)</sub>	peak soldering temperature			-	260	°C
V <sub>ESD</sub>	electrostatic discharge voltage	НВМ		[tbd]	-	V
Source-dra	in diode					
Is	source current	T <sub>mb</sub> = 25 °C	[1]	-	100	Α
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \mu s$ ; $T_{mb} = 25 ^{\circ}C$		-	1888	Α
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 25 A; $V_{sup} \le$ 30 V; $R_{GS}$ = 50 Ω; unclamped; $t_p$ = 6.1 ms	[2]	-	2987	mJ

Continuous current is limited by package. Protected by 100% test



(1) Capped at 100A due to package

Fig. 1. Continuous drain current as a function of mounting base temperature

$$V_{GS} \ge 10V$$

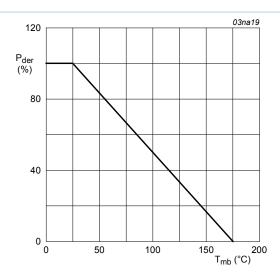


Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

### 8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	Fig. 5	-	0.35	0.43	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	Fig. 3 Fig. 4	-	50 125	-	K/W K/W

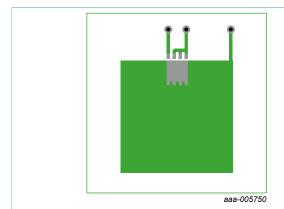


Fig. 3. PCB layout for thermal resistance junction to ambient 1" square pad; FR4 Board; 2oz copper

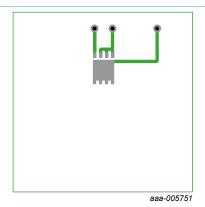
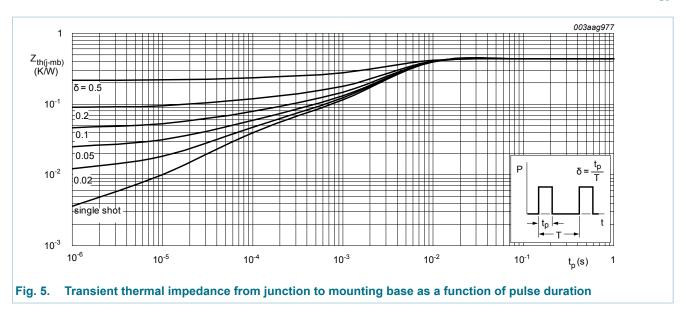


Fig. 4. PCB layout for thermal resistance junction to ambient minimum footprint; FR4 Board; 2oz copper



### 9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static charac	cteristics					
V <sub>(BR)DSS</sub> drain-source breakdown voltage	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 ^{\circ}C$	30	-	-	V
	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V	
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	1.2	[tbd]	2.2	V
$\Delta V_{GS(th)}/\Delta T$	gate-source threshold voltage variation with temperature	25 °C ≤ T <sub>j</sub> ≤ 150 °C	-	[tbd]	-	mV/K
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 24 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	1	μA
		V <sub>DS</sub> = 24 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	100	μA
I <sub>GSS</sub>	gate leakage current	V <sub>GS</sub> = 16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
		V <sub>GS</sub> = -16 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	-	100	nA
R <sub>DSon</sub>	drain-source on-state	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C	-	0.97	1.09	mΩ
	resistance	V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 150 °C; Fig. 6	-	-	1.8	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C	-	0.77	0.87	mΩ
		$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 150 °C; Fig. 6	-	-	1.44	mΩ
$R_G$	gate resistance	f = 1 MHz	-	1.2	-	Ω

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Dynamic ch	naracteristics						
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 15 \text{ V}; V_{GS} = 10 \text{ V};$ Fig. 7		-	[tbd]	-	nC
		$I_D$ = 25 A; $V_{DS}$ = 15 V; $V_{GS}$ = 4.5 V; Fig. 7		-	[tbd]	-	nC
		I <sub>D</sub> = 0 A; V <sub>DS</sub> = 0 V; V <sub>GS</sub> = 10 V		-	[tbd]	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 15 \text{ V}; V_{GS} = 4.5 \text{ V};$		-	[tbd]	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate- source charge	<u>Fig. 7</u>		-	[tbd]	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate- source charge			-	[tbd]	-	nC
$Q_{GD}$	gate-drain charge			-	[tbd]	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 15 V; <u>Fig. 7</u>		-	[tbd]	-	V
C <sub>iss</sub>	input capacitance	$V_{DS}$ = 15 V; $V_{GS}$ = 0 V; f = 1 MHz; $T_j$ = 25 °C		-	[tbd]	-	pF
C <sub>oss</sub>	output capacitance			-	[tbd]	-	pF
C <sub>rss</sub>	reverse transfer capacitance			-	[tbd]	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 15 V; $R_L$ = 0.6 $\Omega$ ; $V_{GS}$ = 4.5 V;		-	[tbd]	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 5 \Omega$		-	[tbd]	-	ns
$t_{\text{d(off)}}$	turn-off delay time			-	[tbd]	-	ns
t <sub>f</sub>	fall time	_		-	[tbd]	-	ns
Q <sub>oss</sub>	output charge	$V_{GS} = 0 \text{ V}; V_{DS} = 15 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$		-	[tbd]	-	nC
Source-dra	in diode					1	
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$		-	[tbd]	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 25 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;		-	[tbd]	-	ns
Q <sub>r</sub>	recovered charge	V <sub>DS</sub> = 15 V; <u>Fig. 8</u>	[1]	-	[tbd]	-	nC
t <sub>a</sub>	reverse recovery rise time			-	[tbd]	-	ns
t <sub>b</sub>	reverse recovery fall time			-	[tbd]	-	ns
S	softness factor	_		-	[tbd]	-	

<sup>[1]</sup> includes capacitive recovery

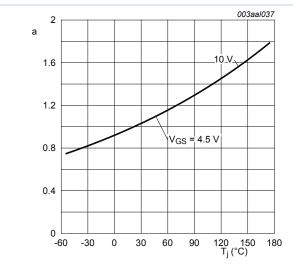


Fig. 6. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon (25^{\circ}C)}}$$

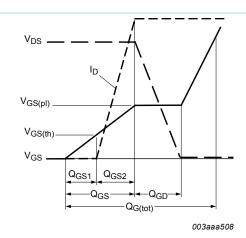


Fig. 7. Gate charge waveform definitions

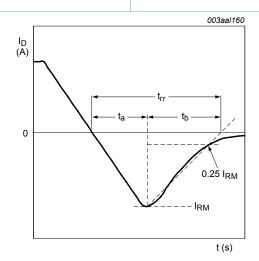
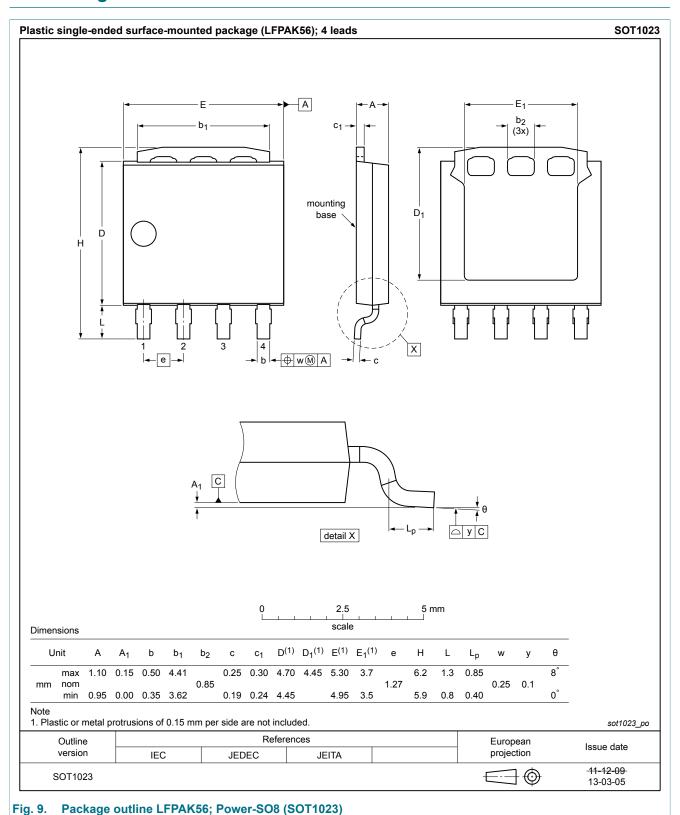


Fig. 8. Reverse recovery timing definition

## 10. Package outline



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